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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	AVR
Core Size	8-Bit
Speed	10MHz
Connectivity	I ² C, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	32
Program Memory Size	32KB (16K x 16)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	44-TQFP
Supplier Device Package	44-TQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atmega324pv-10au

Summary of Features

- Up to 6 serial interface channels to be used as UART, LIN, high-speed synchronous channel (SPI/QSPI), IIC bus interface (10-bit addressing, 400 kbit/s), IIS interface
- On-chip MultiCAN interface (Rev. 2.0B active) with up to 128 message objects (Full CAN/Basic CAN) on up to 5 CAN nodes and gateway functionality
- On-chip real time clock
- Up to 12 Mbytes external address space for code and data
 - Programmable external bus characteristics for different address ranges
 - Multiplexed or demultiplexed external address/data buses
 - Selectable address bus width
 - 16-bit or 8-bit data bus width
 - Five programmable chip-select signals
 - Hold- and hold-acknowledge bus arbitration support
- Single power supply from 3.0 V to 5.5 V
- Programmable watchdog timer and oscillator watchdog
- Up to 118 general purpose I/O lines
- On-chip bootstrap loaders
- Supported by a full range of development tools including C compilers, macro-assembler packages, emulators, evaluation boards, HLL debuggers, simulators, logic analyzer disassemblers, programming boards
- On-chip debug support via JTAG interface
- 144-pin Green LQFP package, 0.5 mm (19.7 mil) pitch

Ordering Information

The ordering code for an Infineon microcontroller provides an exact reference to a specific product. This ordering code identifies:

- the derivative itself, i.e. its function set, the temperature range, and the supply voltage
- the package and the type of delivery.

For ordering codes for the XE167 please contact your sales representative or local distributor.

This document describes several derivatives of the XE167 group. **Table 1** lists these derivatives and summarizes the differences. As this document refers to all of these derivatives, some descriptions may not apply to a specific product.

For simplicity the term **XE167** is used for all derivatives throughout this document.

Summary of Features

Table 1 XE167 Derivative Synopsis

Derivative¹⁾	Temp. Range	Program Memory²⁾	PSRAM³⁾	CCU6 Mod.	ADC⁴⁾ Chan.	Interfaces⁴⁾
SAF-XE167F-48F66L	-40 °C to 85 °C	384 Kbytes Flash	16 Kbytes	0, 1, 2, 3	16 + 8	5 CAN Nodes, 6 Serial Chan.
SAF-XE167F-72F66L	-40 °C to 85 °C	576 Kbytes Flash	32 Kbytes	0, 1, 2, 3	16 + 8	5 CAN Nodes, 6 Serial Chan.
SAF-XE167F-96FxxL	-40 °C to 85 °C	768 Kbytes Flash	64 Kbytes	0, 1, 2, 3	16 + 8	5 CAN Nodes, 6 Serial Chan.
SAF-XE167G-48F66L	-40 °C to 85 °C	384 Kbytes Flash	16 Kbytes	0, 1	8 + 8	2 CAN Nodes, 4 Serial Chan.
SAF-XE167G-72F66L	-40 °C to 85 °C	576 Kbytes Flash	32 Kbytes	0, 1	8 + 8	2 CAN Nodes, 4 Serial Chan.
SAF-XE167G-96F66L	-40 °C to 85 °C	768 Kbytes Flash	64 Kbytes	0, 1	8 + 8	2 CAN Nodes, 4 Serial Chan.
SAF-XE167H-48F66L	-40 °C to 85 °C	384 Kbytes Flash	16 Kbytes	0, 1, 2, 3	16 + 8	No CAN Node, 6 Serial Chan.
SAF-XE167H-72F66L	-40 °C to 85 °C	576 Kbytes Flash	32 Kbytes	0, 1, 2, 3	16 + 8	No CAN Node, 6 Serial Chan.
SAF-XE167H-96F66L	-40 °C to 85 °C	768 Kbytes Flash	64 Kbytes	0, 1, 2, 3	16 + 8	No CAN Node, 6 Serial Chan.
SAF-XE167K-48F66L	-40 °C to 85 °C	384 Kbytes Flash	16 Kbytes	0, 1	8 + 8	No CAN Node, 4 Serial Chan.
SAF-XE167K-72F66L	-40 °C to 85 °C	576 Kbytes Flash	32 Kbytes	0, 1	8 + 8	No CAN Node, 4 Serial Chan.
SAF-XE167K-96F66L	-40 °C to 85 °C	768 Kbytes Flash	64 Kbytes	0, 1	8 + 8	No CAN Node, 4 Serial Chan.

1) This Data Sheet is valid for devices starting with and including design step AC.

2) Specific information about the on-chip Flash memory in [Table 2](#).

3) All derivatives additionally provide 1 Kbyte SBRAM, 2 Kbytes DPRAM, and 16 Kbytes DSRAM.

4) Specific information about the available channels in [Table 3](#).

Analog input channels are listed for each Analog/Digital Converter module separately (ADC0 + ADC1).

Table 4 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
12	P7.4	O0 / I	St/B	Bit 4 of Port 7, General Purpose Input/Output
	EMUX2	O1	St/B	External Analog MUX Control Output 2 (ADC1)
	U0C1_DOUT	O2	St/B	USIC0 Channel 1 Shift Data Output
	U0C1_SCLKOUT	O3	St/B	USIC0 Channel 1 Shift Clock Output
	CCU62_CCPOS2A	I	St/B	CCU62 Position Input 2
	TCK_C	I	St/B	JTAG Clock Input
	U0C0_DX0D	I	St/B	USIC0 Channel 0 Shift Data Input
	U0C1_DX1E	I	St/B	USIC0 Channel 1 Shift Clock Input
13	P8.1	O0 / I	St/B	Bit 1 of Port 8, General Purpose Input/Output
	CCU60_CC61	O1 / I	St/B	CCU60 Channel 1 Input/Output
14	P8.0	O0 / I	St/B	Bit 0 of Port 8, General Purpose Input/Output
	CCU60_CC60	O1 / I	St/B	CCU60 Channel 0 Input/Output
16	P6.0	O0 / I	St/A	Bit 0 of Port 6, General Purpose Input/Output
	EMUX0	O1	St/A	External Analog MUX Control Output 0 (ADC0)
	BRKOUT	O3	St/A	OCDS Break Signal Output
	ADCx_REQGTyC	I	St/A	External Request Gate Input for ADC0/1
	U1C1_DX0E	I	St/A	USIC1 Channel 1 Shift Data Input
17	P6.1	O0 / I	St/A	Bit 1 of Port 6, General Purpose Input/Output
	EMUX1	O1	St/A	External Analog MUX Control Output 1 (ADC0)
	T3OUT	O2	St/A	GPT1 Timer T3 Toggle Latch Output
	U1C1_DOUT	O3	St/A	USIC1 Channel 1 Shift Data Output
	ADCx_REQTRyC	I	St/A	External Request Trigger Input for ADC0/1

Table 4 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
87	P0.3	O0 / I	St/B	Bit 3 of Port 0, General Purpose Input/Output
	U1C0_SELO0	O1	St/B	USIC1 Channel 0 Select/Control 0 Output
	U1C1_SELO1	O2	St/B	USIC1 Channel 1 Select/Control 1 Output
	CCU61_COUT60	O3	St/B	CCU61 Channel 0 Output
	A3	OH	St/B	External Bus Interface Address Line 3
	U1C0_DX2A	I	St/B	USIC1 Channel 0 Shift Control Input
	RxDC0B	I	St/B	CAN Node 0 Receive Data Input
88	P3.1	O0 / I	St/B	Bit 1 of Port 3, General Purpose Input/Output
	U2C0_DOUT	O1	St/B	USIC2 Channel 0 Shift Data Output
	TxDC3	O2	St/B	CAN Node 3 Transmit Data Output
	HLDA	OH / I	St/B	External Bus Hold Acknowledge Output/Input Output in master mode, input in slave mode.
	U2C0_DX0B	I	St/B	USIC2 Channel 0 Shift Data Input
89	P10.2	O0 / I	St/B	Bit 2 of Port 10, General Purpose Input/Output
	U0C0_SCLKOUT	O1	St/B	USIC0 Channel 0 Shift Clock Output
	CCU60_CC62	O2 / I	St/B	CCU60 Channel 2 Input/Output
	AD2	OH / I	St/B	External Bus Interface Address/Data Line 2
	U0C0_DX1B	I	St/B	USIC0 Channel 0 Shift Clock Input
90	P0.4	O0 / I	St/B	Bit 4 of Port 0, General Purpose Input/Output
	U1C1_SELO0	O1	St/B	USIC1 Channel 1 Select/Control 0 Output
	U1C0_SELO1	O2	St/B	USIC1 Channel 0 Select/Control 1 Output
	CCU61_COUT61	O3	St/B	CCU61 Channel 1 Output
	A4	OH	St/B	External Bus Interface Address Line 4
	U1C1_DX2A	I	St/B	USIC1 Channel 1 Shift Control Input
	RxDC1B	I	St/B	CAN Node 1 Receive Data Input

Table 4 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
122	P9.3	O0 / I	St/B	Bit 3 of Port 9, General Purpose Input/Output
	CCU63_COUT60	O1	St/B	CCU63 Channel 0 Output
	$\overline{\text{BRKOUT}}$	O2	St/B	OCDS Break Signal Output
123	P10.13	O0 / I	St/B	Bit 13 of Port 10, General Purpose Input/Output
	U1C0_DOUT	O1	St/B	USIC1 Channel 0 Shift Data Output
	TxDC3	O2	St/B	CAN Node 3 Transmit Data Output
	U1C0_SELO3	O3	St/B	USIC1 Channel 0 Select/Control 3 Output
	$\overline{\text{WR/WRL}}$	OH	St/B	External Bus Interface Write Strobe Output Active for each external write access, when $\overline{\text{WR}}$, active for ext. writes to the low byte, when $\overline{\text{WRL}}$.
	U1C0_DX0D	I	St/B	USIC1 Channel 0 Shift Data Input
124	P1.3	O0 / I	St/B	Bit 3 of Port 1, General Purpose Input/Output
	CCU62_COUT63	O1	St/B	CCU62 Channel 3 Output
	U1C0_SELO7	O2	St/B	USIC1 Channel 0 Select/Control 7 Output
	U2C0_SELO4	O3	St/B	USIC2 Channel 0 Select/Control 4 Output
	A11	OH	St/B	External Bus Interface Address Line 11
	ESR2_4	I	St/B	ESR2 Trigger Input 4
	CCU62_T12HRB	I	St/B	External Run Control Input for T12 of CCU62
	EX3AINA	I	St/B	External Interrupt Trigger Input
125	P9.4	O0 / I	St/B	Bit 4 of Port 9, General Purpose Input/Output
	CCU63_COUT61	O1	St/B	CCU63 Channel 1 Output
	U2C0_DOUT	O2	St/B	USIC2 Channel 0 Shift Data Output

Table 4 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
135	P1.7	O0 / I	St/B	Bit 7 of Port 1, General Purpose Input/Output
	CCU62_ CC60	O1 / I	St/B	CCU62 Channel 0 Input/Output
	U1C1_ MCLKOUT	O2	St/B	USIC1 Channel 1 Master Clock Output
	U2C0_ SCLKOUT	O3	St/B	USIC2 Channel 0 Shift Clock Output
	A15	OH	St/B	External Bus Interface Address Line 15
	U2C0_DX1C	I	St/B	USIC2 Channel 0 Shift Clock Input
136	XTAL2	O	Sp/1	Crystal Oscillator Amplifier Output
137	XTAL1	I	Sp/1	Crystal Oscillator Amplifier Input To clock the device from an external source, drive XTAL1, while leaving XTAL2 unconnected. Voltages on XTAL1 must comply to the core supply voltage V_{DDI1} .
138	$\overline{\text{PORST}}$	I	In/B	Power On Reset Input A low level at this pin resets the XE167 completely. A spike filter suppresses input pulses <10 ns. Input pulses >100 ns safely pass the filter. The minimum duration for a safe recognition should be 120 ns. An internal pullup device will hold this pin high when nothing is driving it.
139	$\overline{\text{ESR1}}$	O0 / I	St/B	External Service Request 1
	U1C0_DX0F	I	St/B	USIC1 Channel 0 Shift Data Input
	U1C0_DX2C	I	St/B	USIC1 Channel 0 Shift Control Input
	U1C1_DX0C	I	St/B	USIC1 Channel 1 Shift Data Input
	U1C1_DX2B	I	St/B	USIC1 Channel 1 Shift Control Input
	U2C1_DX2C	I	St/B	USIC2 Channel 1 Shift Control Input
	EX0AINB	I	St/B	External Interrupt Trigger Input

Functional Description

1024 bytes (2 × 512 bytes) of the address space are reserved for the Special Function Register areas (SFR space and ESFR space). SFRs are word-wide registers which are used to control and monitor functions of the different on-chip units. Unused SFR addresses are reserved for future members of the XE166 Family. In order to ensure upward compatibility they should either not be accessed or written with zeros.

In order to meet the requirements of designs where more memory is required than is available on chip, up to 12 Mbytes (approximately, see [Table 5](#)) of external RAM and/or ROM can be connected to the microcontroller. The External Bus Interface also provides access to external peripherals.

Up to 768 Kbytes of on-chip Flash memory store code, constant data, and control data. The on-chip Flash memory consists of up to three modules with a maximum capacity of 256 Kbytes each. Each module is organized in 4-Kbyte sectors.

The uppermost 4-Kbyte sector of segment 0 (located in Flash module 0) is used internally to store operation control parameters and protection information.

Note: The actual size of the Flash memory depends on the chosen derivative (see [Table 1](#)).

Each sector can be separately write protected¹⁾, erased and programmed (in blocks of 128 Bytes). The complete Flash area can be read-protected. A user-defined password sequence temporarily unlocks protected areas. The Flash modules combine 128-bit read access with protected and efficient writing algorithms for programming and erasing. Dynamic error correction provides extremely high read data security for all read access operations. Access to different Flash modules can be executed in parallel.

For Flash parameters, please see [Section 4.5](#).

1) To save control bits, sectors are clustered for protection purposes, they remain separate for programming/erasing.

3.2 External Bus Controller

All external memory access operations are performed by a special on-chip External Bus Controller (EBC). The EBC also controls access to resources connected to the on-chip LXBus (MultiCAN and the USIC modules). The LXBus is an internal representation of the external bus that allows access to integrated peripherals and modules in the same way as to external components.

The EBC can be programmed either to Single Chip Mode, when no external memory is required, or to an external bus mode with the following selections¹⁾:

- Address Bus Width with a range of 0 ... 24-bit
- Data Bus Width 8-bit or 16-bit
- Bus Operation Multiplexed or Demultiplexed

The bus interface uses Port 10 and Port 2 for addresses and data. In the demultiplexed bus modes, the lower addresses are output separately on Port 0 and Port 1. The number of active segment address lines is selectable, restricting the external address space to 8 Mbytes ... 64 Kbytes. This is required when interface lines shall be assigned to Port 2.

Up to five external $\overline{\text{CS}}$ signals (four windows plus default) can be generated and output on Port 4 in order to save external glue logic. External modules can be directly connected to the common address/data bus and their individual select lines.

A $\overline{\text{HOLD}}/\overline{\text{HLDA}}$ protocol is available for bus arbitration; this allows the sharing of external resources with other bus masters. The bus arbitration is enabled by software, after which pins P3.0 ... P3.2 ($\overline{\text{BREQ}}$, $\overline{\text{HLDA}}$, $\overline{\text{HOLD}}$) are automatically controlled by the EBC. In Master Mode (default after reset) the $\overline{\text{HLDA}}$ pin is an output. In Slave Mode pin $\overline{\text{HLDA}}$ is switched to be an input. This allows the direct connection of the slave controller to another master controller without glue logic.

Important timing characteristics of the external bus interface are programmable (with registers TCONCSx/FCONCSx) to allow the user to adapt it to a wide range of different types of memories and external peripherals.

Access to very slow memories or modules with varying access times is supported by a special 'Ready' function. The active level of the control input signal is selectable.

In addition, up to four independent address windows may be defined (using registers ADDRSELx) to control access to resources with different bus characteristics. These address windows are arranged hierarchically where window 4 overrides window 3, and window 2 overrides window 1. All accesses to locations not covered by these four address windows are controlled by TCONCS0/FCONCS0. The currently active window can generate a chip select signal.

The external bus timing is based on the rising edge of the reference clock output CLKOUT. The external bus protocol is compatible with that of the standard C166 Family.

1) Bus modes are switched dynamically if several address windows with different mode settings are used.

3.6 Capture/Compare Unit (CAPCOM2)

The CAPCOM2 unit supports generation and control of timing sequences on up to 16 channels with a maximum resolution of one system clock cycle (eight cycles in staggered mode). The CAPCOM2 unit is typically used to handle high-speed I/O tasks such as pulse and waveform generation, pulse width modulation (PWM), digital to analog (D/A) conversion, software timing, or time recording with respect to external events.

Two 16-bit timers (T7/T8) with reload registers provide two independent time bases for the capture/compare register array.

The input clock for the timers is programmable to a number of prescaled values of the internal system clock. It may also be derived from an overflow/underflow of timer T6 in module GPT2. This provides a wide range for the timer period and resolution while allowing precise adjustments for application-specific requirements. An external count input for CAPCOM2 timer T7 allows event scheduling for the capture/compare registers with respect to external events.

The capture/compare register array contains 16 dual purpose capture/compare registers. Each may be individually allocated to either CAPCOM2 timer T7 or T8 and programmed for a capture or compare function.

Each register of the CAPCOM2 module has one port pin associated with it. This serves as an input pin to trigger the capture function or as an output pin to indicate the occurrence of a compare event.

Table 8 Compare Modes (CAPCOM2)

Compare Modes	Function
Mode 0	Interrupt-only compare mode; Several compare interrupts per timer period are possible
Mode 1	Pin toggles on each compare match; Several compare events per timer period are possible
Mode 2	Interrupt-only compare mode; Only one compare interrupt per timer period is generated
Mode 3	Pin set '1' on match; pin reset '0' on compare timer overflow; Only one compare event per timer period is generated
Double Register Mode	Two registers operate on one pin; Pin toggles on each compare match; Several compare events per timer period are possible
Single Event Mode	Generates single edges or pulses; Can be used with any compare mode

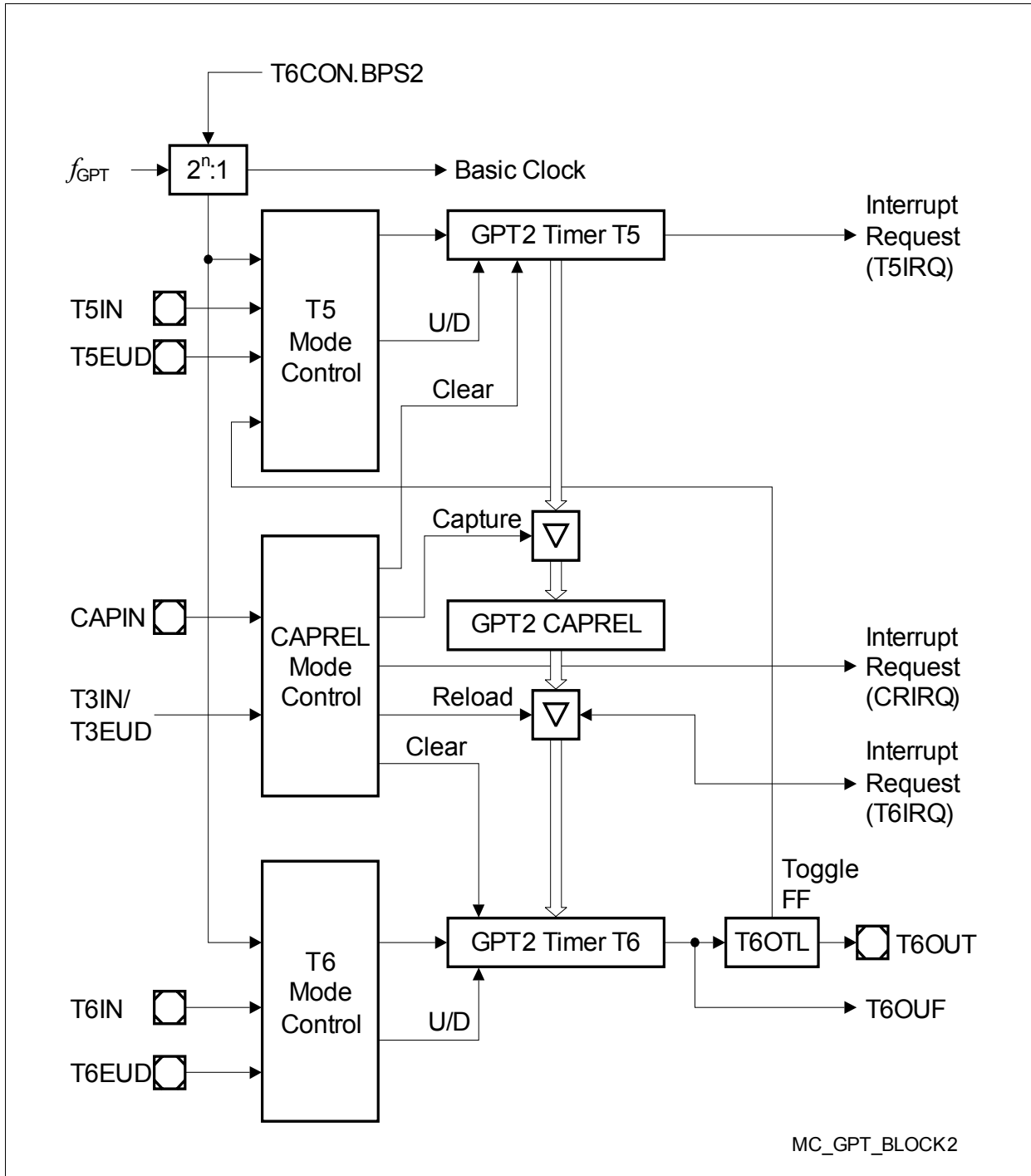


Figure 8 Block Diagram of GPT2

Functional Description

Table 10 Instruction Set Summary (cont'd)

Mnemonic	Description	Bytes
NOP	Null operation	2
CoMUL/CoMAC	Multiply (and accumulate)	4
CoADD/CoSUB	Add/Subtract	4
Co(A)SHR	(Arithmetic) Shift right	4
CoSHL	Shift left	4
CoLOAD/STORE	Load accumulator/Store MAC register	4
CoCMP	Compare	4
CoMAX/MIN	Maximum/Minimum	4
CoABS/CoRND	Absolute value/Round accumulator	4
CoMOV	Data move	4
CoNEG/NOP	Negate accumulator/Null operation	4

- 1) The Enter Power Down Mode instruction is not used in the XE167, due to the enhanced power control scheme. PWRDN will be correctly decoded, but will trigger no action.

Electrical Parameters

Table 12 Operating Condition Parameters (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
External Pin Load Capacitance	C_L	–	20	–	pF	Pin drivers in default mode ⁶⁾
Voltage Regulator Buffer Capacitance for DMP_M	C_{EVRM}	1.0	–	4.7	μF	⁷⁾
Voltage Regulator Buffer Capacitance for DMP_1	C_{EVR1}	0.47	–	2.2	μF	One for each supply pin ⁷⁾
Operating frequency	f_{SYS}	–	–	80	MHz	⁸⁾
Ambient temperature	T_A	–	–	–	°C	See Table 1

- 1) If both core power domains are clocked, the difference between the power supply voltages must be less than 10 mV. This condition imposes additional constraints when using external power supplies.
Do not combine internal and external supply of different core power domains.
Do not supply the core power domains with two independent external voltage regulators. The simplest method is to supply both power domains directly via a single external power supply.
- 2) Performance of pad drivers, A/D Converter, and Flash module depends on V_{DDP} .
If the external supply voltage V_{DDP} becomes lower than the specified operating range, a power reset must be generated. Otherwise, the core supply voltage V_{DDI} may rise above its specified operating range due to parasitic effects.
This power reset can be generated by the on-chip SWD. If the SWD is disabled the power reset must be generated by activating the $\overline{PORST}$ input.
- 3) Overload conditions occur if the standard operating conditions are exceeded, i.e. the voltage on any pin exceeds the specified range: $V_{OV} > V_{IHmax}$ ($I_{OV} > 0$) or $V_{OV} < V_{ILmin}$ ($I_{OV} < 0$). The absolute sum of input overload currents on all pins may not exceed **50 mA**. The supply voltages must remain within the specified limits. Proper operation under overload conditions depends on the application.
Overload conditions must not occur on pin XTAL1 (powered by V_{DDI}).
- 4) Not subject to production test - verified by design/characterization.
- 5) An overload current (I_{OV}) through a pin injects an error current (I_{NJ}) into the adjacent pins. This error current adds to that pin's leakage current (I_{OZ}). The value of the error current depends on the overload current and is defined by the overload coupling factor K_{OV} . The polarity of the injected error current is reversed from the polarity of the overload current that produces it.
The total current through a pin is $|I_{TOT}| = |I_{OZ}| + (|I_{OV}| \times K_{OV})$. The additional error current may distort the input voltage on analog inputs.
- 6) The timing is valid for pin drivers operating in default current mode (selected after reset). Reducing the output current may lead to increased delays or reduced driving capability (C_L).
- 7) To ensure the stability of the voltage regulators the EVRs must be buffered with ceramic capacitors. Separate buffer capacitors with the recommended values shall be connected as close as possible to each V_{DDI} pin to keep the resistance of the board tracks below 2 Ω. Connect all V_{DDI1} pins together.
The minimum capacitance value is required for proper operation under all conditions (e.g. temperature). Higher values slightly increase the startup time.
- 8) The operating frequency range may be reduced for specific types of the **XE167**. This is indicated in the device designation (...FxxL). 80-MHz devices are marked ...F80L.

Table 18 A/D Converter Characteristics (cont'd)
(Operating Conditions apply)

Parameter	Symbol		Limit Values		Unit	Test Condition
			Min.	Max.		
Switched capacitance of the reference input	C_{AREFS}	CC	–	7	pF	6)7)
Resistance of the reference input path	R_{AREF}	CC	–	2	k Ω	6)7)

- 1) TUE is tested at $V_{AREFX} = V_{DDPA}$, $V_{AGND} = 0$ V. It is verified by design for all other voltages within the defined voltage range.
The specified TUE is valid only if the absolute sum of input overload currents on Port 5 or Port 15 pins (see I_{OV} specification) does not exceed 10 mA, and if V_{AREF} and V_{AGND} remain stable during the measurement time.
- 2) V_{AIN} may exceed V_{AGND} or V_{AREFX} up to the absolute maximum ratings. However, the conversion result in these cases will be X000_H or X3FF_H, respectively.
- 3) The limit values for f_{ADCI} must not be exceeded when selecting the peripheral frequency and the prescaler setting.
- 4) This parameter includes the sample time (also the additional sample time specified by STC), the time to determine the digital result and the time to load the result register with the conversion result.
Values for the basic clock t_{ADCI} depend on programming and are found in [Table 19](#).
- 5) The total unadjusted error TUE is the maximum deviation from the ideal ADC transfer curve, not the sum of individual errors.
All error specifications are based on measurement methods standardized by IEEE 1241.2000.
- 6) Not subject to production test - verified by design/characterization.
- 7) These parameter values cover the complete operating range. Under relaxed operating conditions (temperature, supply voltage) typical values can be used for calculation. At room temperature and nominal supply voltage the following typical values can be used:
 $C_{AINTtyp} = 12$ pF, $C_{AINStyp} = 5$ pF, $R_{AINTtyp} = 1.0$ k Ω , $C_{AREFTtyp} = 15$ pF, $C_{AREFStyp} = 10$ pF, $R_{AREFTyp} = 1.0$ k Ω .

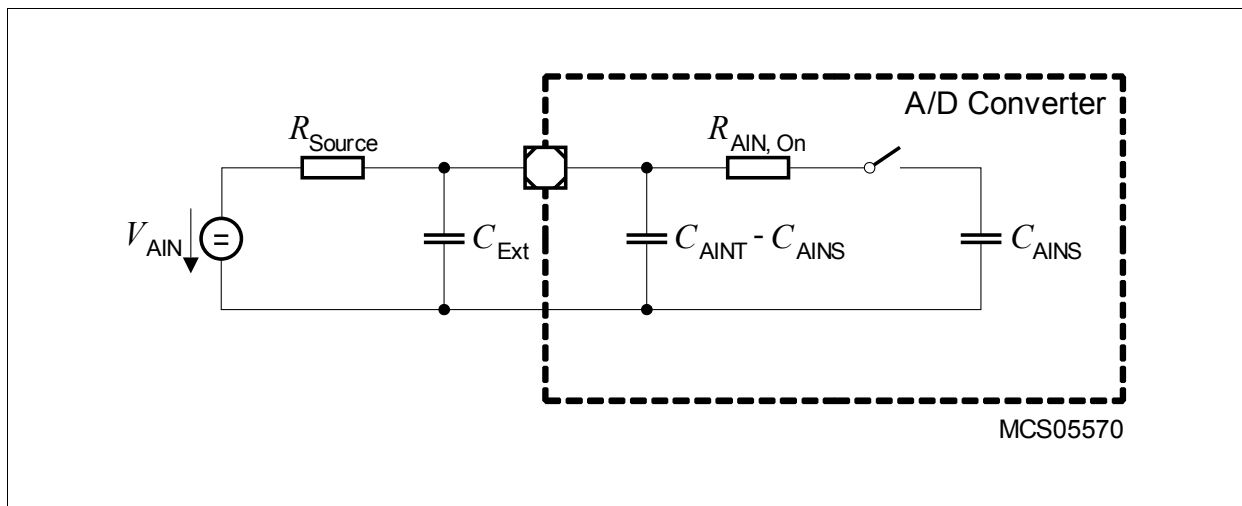


Figure 15 Equivalent Circuitry for Analog Inputs

4.4 System Parameters

The following parameters specify several aspects which are important when integrating the XE167 into an application system.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Table 20 Various System Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Supply watchdog (SWD) supervision level (see Table 21)	V_{SWD} CC	$V_{\text{LV}} - 0.150$	V_{LV}	$V_{\text{LV}} + 0.100$	V	V_{LV} = selected voltage in upper voltage area
		$V_{\text{LV}} - 0.125$	V_{LV}	$V_{\text{LV}} + 0.050$	V	V_{LV} = selected voltage in lower voltage area
Core voltage (PVC) supervision level (see Table 22)	V_{PVC} CC	$V_{\text{LV}} - 0.070$	V_{LV}	$V_{\text{LV}} + 0.030$	V	V_{LV} = selected voltage
Current control limit	I_{CC} CC	13	–	30	mA	Power domain DMP_M
		90	–	150	mA	Power domain DMP_1
Wakeup clock source frequency	f_{WU} CC	400	500	600	kHz	FREQSEL = 00 _B
Internal clock source frequency	f_{INT} CC	4.8	5.0	5.2	MHz	
Startup time from stopover mode	t_{SSO} CC	200	260	320	μs	User instruction from PSRAM

4.6 AC Parameters

These parameters describe the dynamic behavior of the XE167.

4.6.1 Testing Waveforms

These values are used for characterization and production testing (except pin XTAL1).

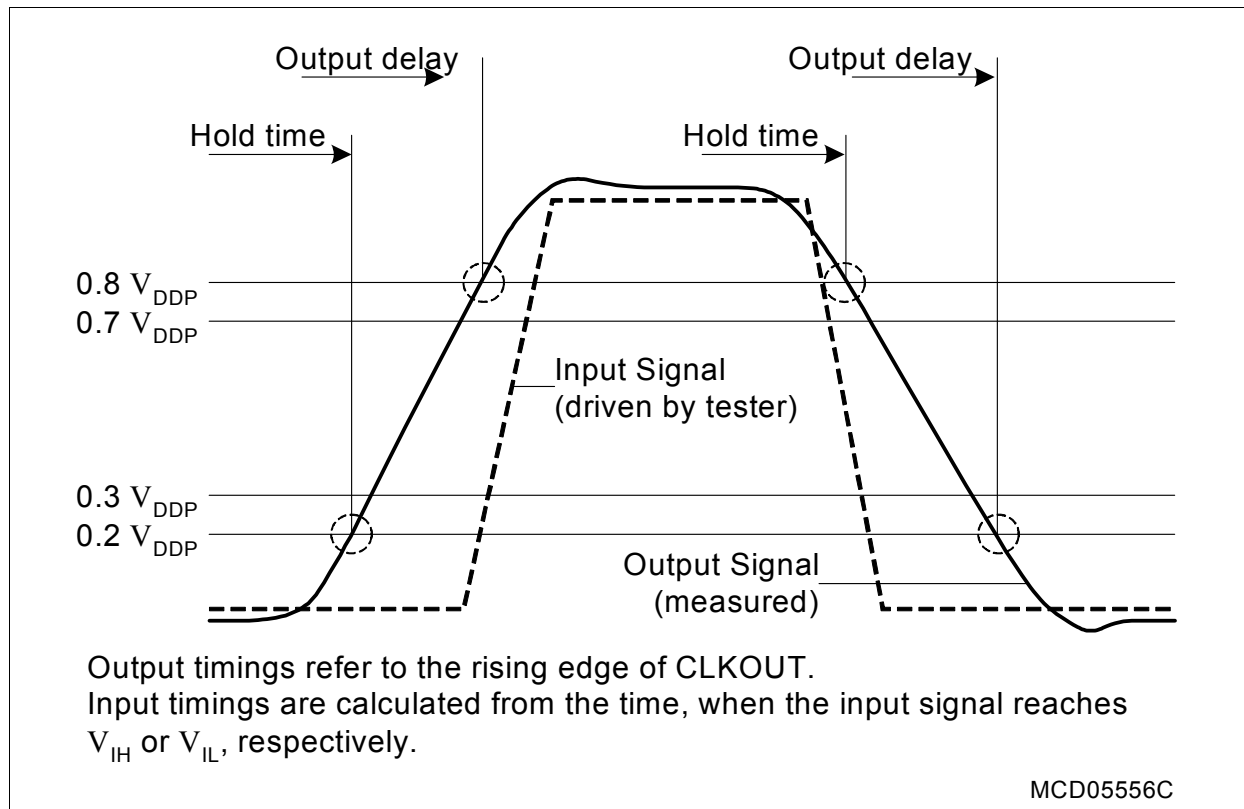


Figure 16 Input Output Waveforms

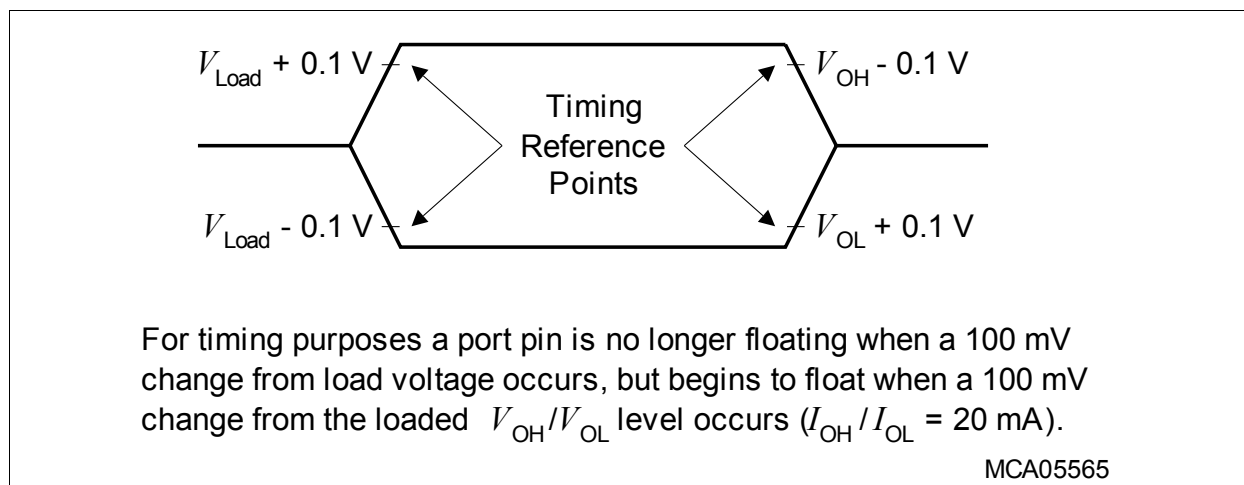


Figure 17 Floating Waveforms

4.6.3 External Clock Input Parameters

These parameters specify the external clock generation for the XE167. The clock can be generated in two ways:

- By connecting a **crystal or ceramic resonator** to pins XTAL1/XTAL2.
- By supplying an **external clock signal**. This clock signal can be supplied either to pin XTAL1 (core voltage domain) or to pin CLKIN1 (IO voltage domain).

If connected to CLKIN1, the input signal must reach the defined input levels V_{IL} and V_{IH} . In connected to XTAL1, a minimum amplitude V_{AX1} (peak-to-peak voltage) is sufficient for the operation of the on-chip oscillator.

Note: The given clock timing parameters ($t_1 \dots t_4$) are only valid for an external clock input signal.

Table 26 External Clock Input Characteristics
(Operating Conditions apply)

Parameter	Symbol	Limit Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input voltage range limits for signal on XTAL1	V_{IX1} SR	$-1.7 + V_{DDI}$	–	1.7	V	1)
Input voltage (amplitude) on XTAL1	V_{AX1} SR	$0.3 \times V_{DDI}$	–	–	V	Peak-to-peak voltage ²⁾
XTAL1 input current	I_{IL} CC	–	–	± 20	μA	$0 V < V_{IN} < V_{DDI}$
Oscillator frequency	f_{OSC} CC	4	–	40	MHz	Clock signal
		4	–	16	MHz	Crystal or Resonator
High time	t_1 SR	6	–	–	ns	
Low time	t_2 SR	6	–	–	ns	
Rise time	t_3 SR	–	8	8	ns	
Fall time	t_4 SR	–	8	8	ns	

1) Overload conditions must not occur on pin XTAL1.

2) The amplitude voltage V_{AX1} refers to the offset voltage V_{OFF} . This offset voltage must be stable during the operation and the resulting voltage peaks must remain within the limits defined by V_{IX1} .

4.6.4 External Bus Timing

The following parameters specify the behavior of the XE167 bus interface.

Table 27 CLKOUT Reference Signal

Parameter	Symbol		Limits		Unit	Note / Test Condition
			Min.	Max.		
CLKOUT cycle time	t_5	CC	40/25/12.5 ¹⁾		ns	
CLKOUT high time	t_6	CC	3	—	ns	
CLKOUT low time	t_7	CC	3	—	ns	
CLKOUT rise time	t_8	CC	—	3	ns	
CLKOUT fall time	t_9	CC	—	3	ns	

1) The CLKOUT cycle time is influenced by the PLL jitter (given values apply to $f_{SYS} = 25/40/80$ MHz).
For longer periods the relative deviation decreases (see PLL deviation formula).

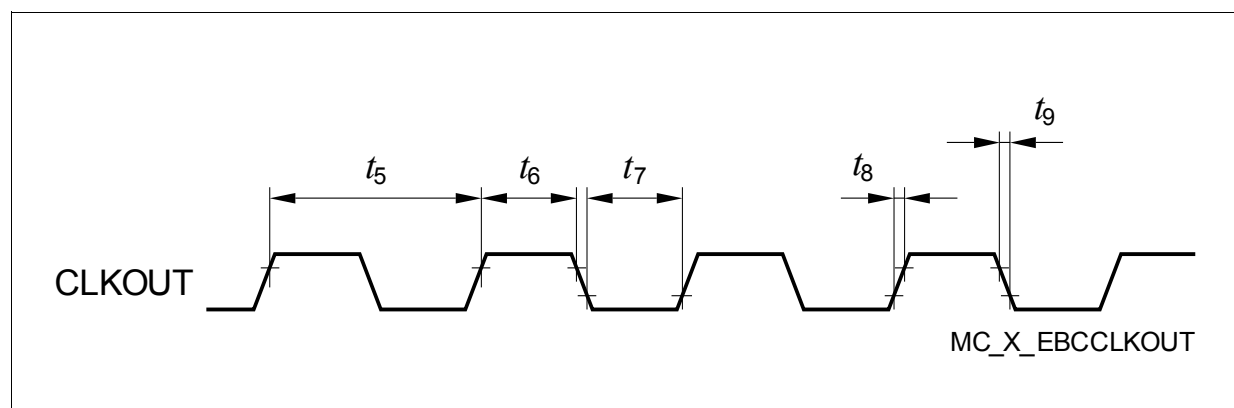


Figure 21 CLKOUT Signal Timing

Note: The term CLKOUT refers to the reference clock output signal which is generated by selecting f_{SYS} as the source signal for the clock output signal EXTCLK on pin P2.8 and by enabling the high-speed clock driver on this pin.

Variable Memory Cycles

External bus cycles of the XE167 are executed in five consecutive cycle phases (AB, C, D, E, F). The duration of each cycle phase is programmable (via the TCONCSx registers) to adapt the external bus cycles to the respective external module (memory, peripheral, etc.).

The duration of the access phase can optionally be controlled by the external module using the READY handshake input.

This table provides a summary of the phases and the ranges for their length.

Table 28 Programmable Bus Cycle Phases (see timing diagrams)

Bus Cycle Phase	Parameter	Valid Values	Unit
Address setup phase, the standard duration of this phase (1 ... 2 TCS) can be extended by 0 ... 3 TCS if the address window is changed	tpAB	1 ... 2 (5)	TCS
Command delay phase	tpC	0 ... 3	TCS
Write Data setup/MUX Tristate phase	tpD	0 ... 1	TCS
Access phase	tpE	1 ... 32	TCS
Address/Write Data hold phase	tpF	0 ... 3	TCS

Note: The bandwidth of a parameter (from minimum to maximum value) covers the whole operating range (temperature, voltage) as well as process variations. Within a given device, however, this bandwidth is smaller than the specified range. This is also due to interdependencies between certain parameters. Some of these interdependencies are described in additional notes (see standard timing).

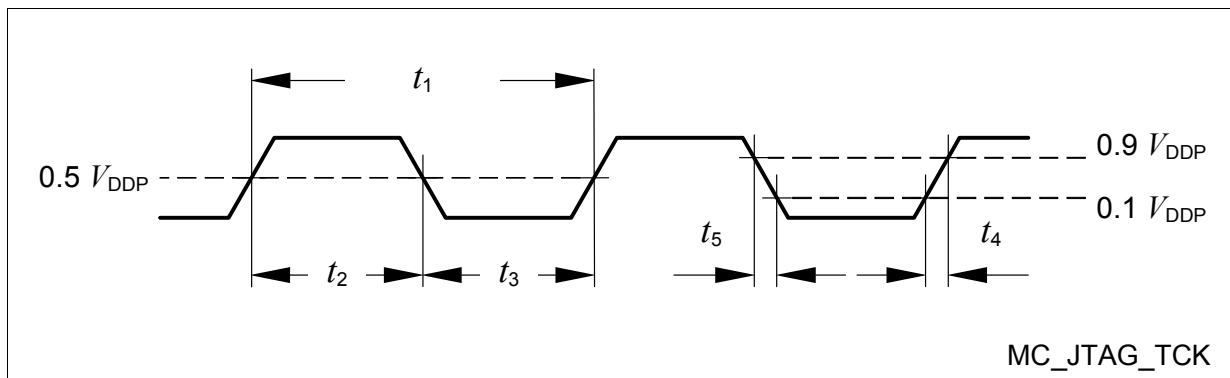


Figure 28 Test Clock Timing (TCK)

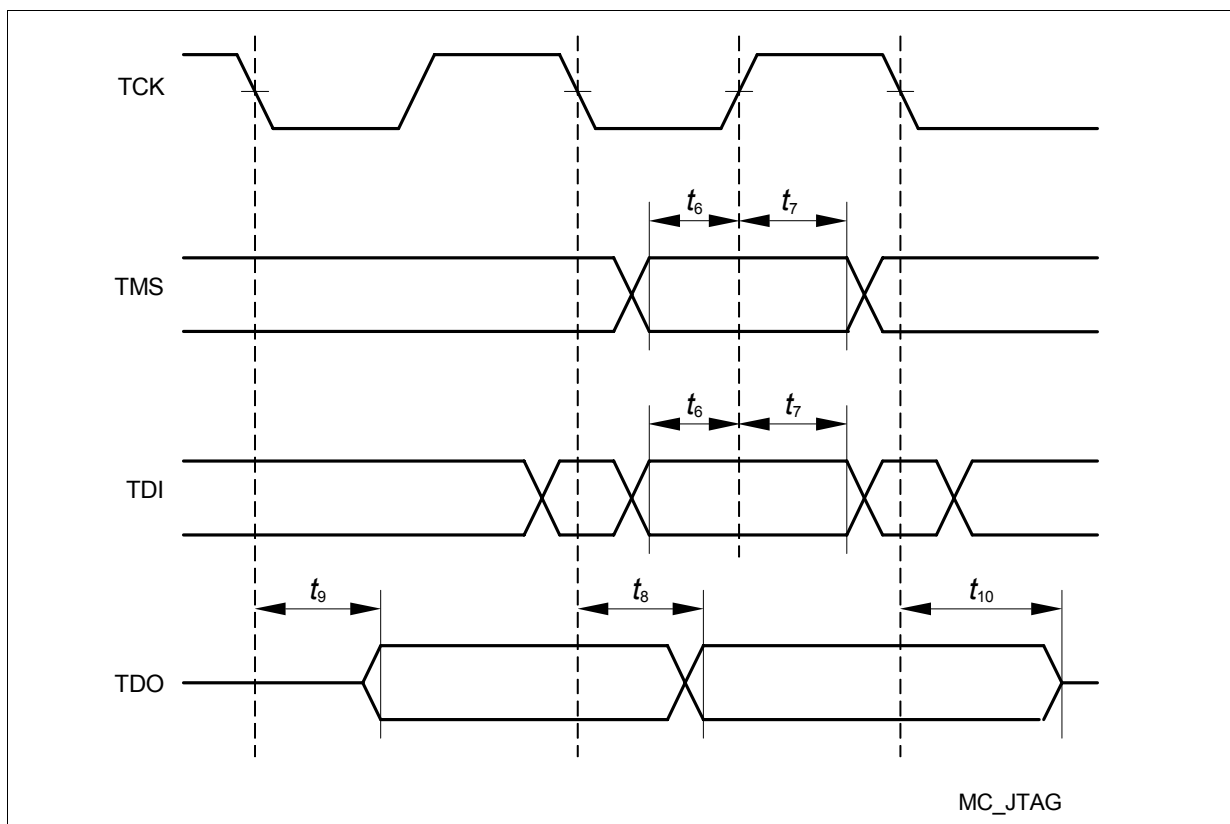


Figure 29 JTAG Timing